

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

EXPRESS MAIL NO. EV351235065US

Appl No. : N/A Confirmation No.
Applicant : Akio Ishikawa
Filed : September 29, 2003
Title : IMAGE DEFECT INSPECTION METHOD, IMAGE DEFECT
INSPECTION APPARATUS AND APPEARANCE INSPECTION
APPARATUS

TC/A.U. : N/A
Examiner : N/A

Docket No. : 51272/DBP/A400
Customer No. : 23363

PRELIMINARY AMENDMENT

Commissioner for Patents Post Office Box 7068
P.O. Box 1450 Pasadena, CA 91109-7068
Alexandria, VA 22313-1450 September 29, 2003

Commissioner:

Prior to examination, please amend the above-identified application as follows:

Amendments to the Specification begin on page 2 of this paper.

Remarks/Arguments begin on page 3 of this paper.